

# **SECOND INFORMATION DISCLOSURE STATEMENT BY APPLICANT**

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Application Number 10/672,889  
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 First Named Inventor James J. Snyder et al.  
 Examiner Name MICHAEL A LYONS  
 Attorney Docket Number 033806-010

**U.S. PATENT DOCUMENTS**

Examiner Initials	Document Number	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Issue/Publication Date (MM-DD-YYYY)

**FOREIGN PATENT DOCUMENTS**

Examiner Initials	Document Number	Kind Code (if known)	Country	Date of Publication (MM-DD-YYYY)	STATUS						
					Translation	Partial Translation	Eng. Lang. Summary	Search Report	IPER	Abstract	Cited in Spec

**NON-PATENT LITERATURE DOCUMENTS**

Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
/HL/	Snyder, J.J., "Algorithm for fast digital analysis of interference fringes", <i>Applied Optics</i> 19, 1223 (1980).
/HL/	J.H. Bruing, "Fringe Scanning Interferometers", in <i>Optical Shop Testing</i> , Daniel Malacara, ed. (John Wiley and Sons, New York, 1978) 409-437.
/HL/	Katherine Creath, "Phase-Measurement Interferometry Techniques," in <i>Progress in Optics XXXVI</i> , E. Wolf, ed. (North-Holland, Amsterdam, 1988), 349-393).

Examiner Signature	/Hwa Lee/	Date Considered	08/07/2007
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.  
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